

Search Notes

Application/Control No.

10/796,141

Examiner

Lee Lum

Applicant(s)/Patent under
Reexamination

OTAKI ET AL.

Art Unit

3611

SEARCHED

Class	Subclass	Date	Examiner
180	421		
	422		
	441		
	442		
91	515A		
	444		
	448		
		a/9/05 ff	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner